Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | NAITO ET AL. | Examiner | David B. Jones | 3725 | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,102,316	09-2006	Beyer et al.	100/178
*	В	US-7,234,337	06-2007	Nagae, Masayuki	72/449
*	C	US-5,299,443	04-1994	Nakamura, Masatoshi	72/446
*	D	US-5,468,194	11-1995	Hayashi, Keiichiro	477/3
*	Е	US-2,771,790	11-1956	MUNSCHAUER FREDERICK E	74/665B
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	J	US-			
	K	US-			
	L	US-			
_	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	EP 0941832	09-1999	EPO		/
	0	JP 10328891	12-1998	Japan		/
	Ρ	DE 19810406 A1	09-1999		Abstract (English)	
	Ø	JP 10328891	12-1998		Abstract (Englsih)	
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.